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Multiattribute Double Sampling Control Chart

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Abstract: In recent years, multiattribute control charts have received an increasing attention. These charts are able to monitor two or more attributes in the same chart. In addition, there are many applications of multi-attribute control charts in a wide variety of manufacturing processes and services. In this article, a multiattribute double sampling (DS D2) chart is proposed. Results of comparative studies via simulation indicate that the proposed control chart significantly outperforms in terms of the Average Run Length.

Keywords: Multiattribute, Control chart, Average Run Length